

STB185N55 STP185N55

N-channel 55V - 2.9mΩ - 120A - D²PAK/TO-220 MDmesh™ low voltage Power MOSFET

TARGET SPECIFICATION

General features

Туре	V _{DSS}	V _{DSS} R _{DS(on)}	
STB185N55	55V	3.5 m Ω	120A ⁽¹⁾
STP185N55	55V	3.8 m Ω	120A ⁽¹⁾

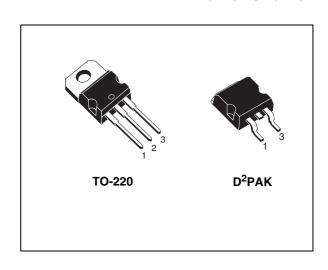
- 1. Value limited by wire bonding
- Ultra low on-resistance
- 100% avalanche tested

Description

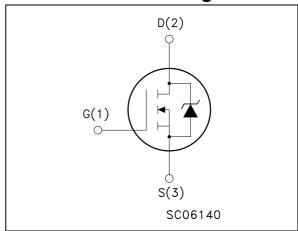
This n-channel enhancement mode Power MOSFET is the latest refinement of STMicroelectronic unique "single feature sizeTM" strip-based process with less critical alignment steps and therefore a remarkable manufacturing reproducibility. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and low gate charge.

Applications

- Switching application
 - Automotive



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STB185N55	B185N55	D ² PAK	Tape & reel
STP185N55	P185N55	TO-220	Tube

Contents

1	Electrical ratings
2	Electrical characteristics 4
3	Test circuit
4	Package mechanical data
5	Packaging mechanical data
6	Revision history

STB185N55 - STP185N55 Electrical ratings

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} =0)	55	V
V _{GS}	Gate-source voltage	± 20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25°C	120	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C =100°C	120	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	480	Α
P _{TOT}	Total dissipation at T _C = 25°C	315	W
	Derating factor	2.1	W/°C
dv/dt	Peak diode recovery voltage slope	Tbd	V/ns
E _{AS} (3)	Single pulse avalanche energy	Tbd	mJ
T _j T _{stg}	Operating junction temperature storage temperature	-55 to 175	°C

^{1.} Current limited by package.

Table 2. Thermal data

		TO-220	D ² PAK	Unit
Rthj-case	Thermal resistance junction-case	0.4	8	°C/W
Rthj-a	Thermal resistance junction-ambient max	62.5		°C/W
Rthj-pcb ⁽¹⁾	Thermal resistance junction-ambient max		35	°C/W
T _I	Maximum lead temperature for soldering purpose	300		°C

^{1.} When mounted o inch² FR4 2oz Cu.

^{2.} Pulse width limited by safe operating area.

^{3.} Starting Tj=25°C, Id=60A, Vdd=40V

2 Electrical characteristics

(T_{CASE} =25°C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter	neter Test conditions		Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250\mu A, V_{GS} = 0$	55			V
I _{DSS}	current (V _{GS} = 0)	V_{DS} = max rating, V_{DS} = max rating, @ 125°C			10 100	μ Α μ Α
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20V			±200	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2		4	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 60A D ² PAK TO-220			3.5 3.8	m Ω

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	V _{DS} = 15V , I _D = 60A		Tbd		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25V, f = 1MHz, V_{GS} = 0$		6200 1800 100		pF pF pF
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} = 27V, I_D = 60A R_G = 4.7 Ω V_{GS} = 10V (see <i>Figure 1</i>)		Tbd Tbd Tbd Tbd		ns ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 44V, I_{D} = 120A, V_{GS} = 10V, R_{G} = 4.7 Ω (see <i>Figure 2</i>)		110 Tbd Tbd	Tbd	nC nC nC

^{1.} Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %.

Table 5. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)				120 480	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} =120A, V _{GS} =0			1.5	٧
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} =120A, V _{DD} = 30V di/dt = 100A/μs, Tj=150°C (see Figure 6)		Tbd Tbd Tbd		ns nC A

^{1.} Pulse width limited by safe operating area

^{2.} Pulsed: pulse duration = 300μ s, duty cycle 1.5%

3 Test circuit

Figure 1. Switching times test circuit for resistive load

Figure 2. Gate charge test circuit

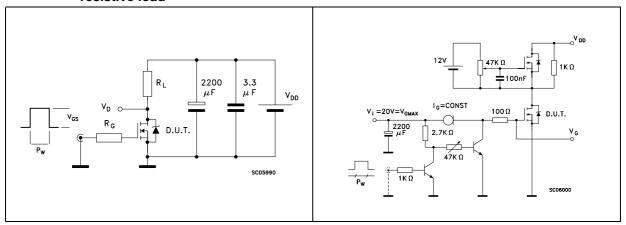


Figure 3. Test circuit for inductive load switching and diode recovery times

Figure 4. Unclamped Inductive load test circuit

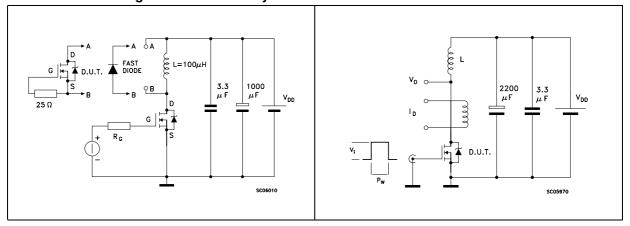
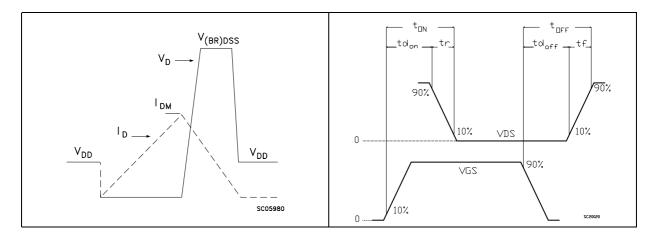


Figure 5. Unclamped inductive waveform

Figure 6. Switching time waveform



577

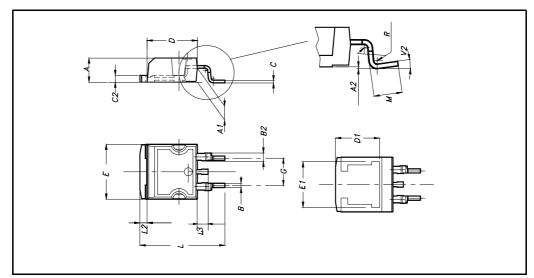
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

7/12

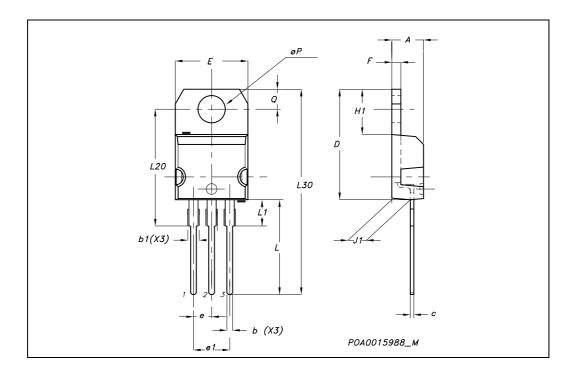
D²PAK MECHANICAL DATA

DIM		mm.			inch		
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.	
Α	4.4		4.6	0.173		0.181	
A1	2.49		2.69	0.098		0.106	
A2	0.03		0.23	0.001		0.009	
В	0.7		0.93	0.027		0.036	
B2	1.14		1.7	0.044		0.067	
С	0.45		0.6	0.017		0.023	
C2	1.23		1.36	0.048		0.053	
D	8.95		9.35	0.352		0.368	
D1		8			0.315		
Е	10		10.4	0.393			
E1		8.5			0.334		
G	4.88		5.28	0.192		0.208	
L	15		15.85	0.590		0.625	
L2	1.27		1.4	0.050		0.055	
L3	1.4		1.75	0.055		0.068	
М	2.4		3.2	0.094		0.126	
R		0.4			0.015		
V2	0º		4º				



TO-220 MECHANICAL DATA

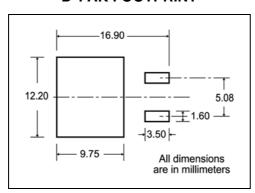
DIM.		mm.			inch			
DIW.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.		
Α	4.40		4.60	0.173		0.181		
b	0.61		0.88	0.024		0.034		
b1	1.15		1.70	0.045		0.066		
С	0.49		0.70	0.019		0.027		
D	15.25		15.75	0.60		0.620		
Е	10		10.40	0.393		0.409		
е	2.40		2.70	0.094		0.106		
e1	4.95		5.15	0.194		0.202		
F	1.23		1.32	0.048		0.052		
H1	6.20		6.60	0.244		0.256		
J1	2.40		2.72	0.094		0.107		
L	13		14	0.511		0.551		
L1	3.50		3.93	0.137		0.154		
L20		16.40			0.645			
L30		28.90			1.137			
øΡ	3.75		3.85	0.147		0.151		
Q	2.65		2.95	0.104		0.116		



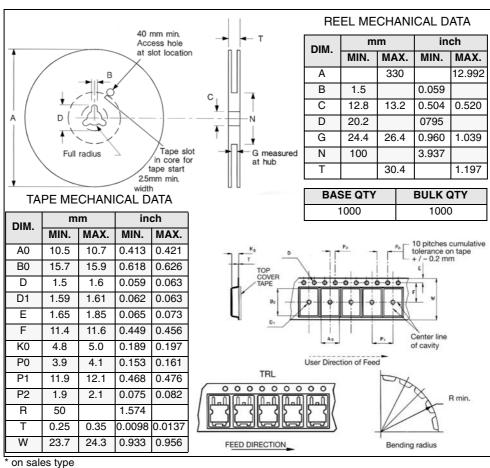
577

Packaging mechanical data 5

D²PAK FOOTPRINT



TAPE AND REEL SHIPMENT



STB185N55 - STP185N55 Revision history

6 Revision history

Table 6. Revision history

Date	Revision	Changes
14-Dec-2005	1	First version
19-Jun-2006	2	New template
01-Aug-2006	3	New value on <i>Dynamic</i>

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2006 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

477